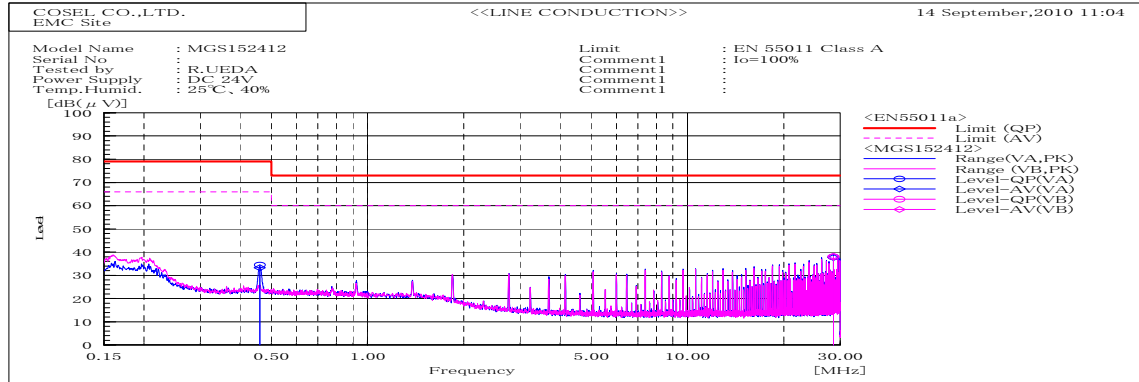
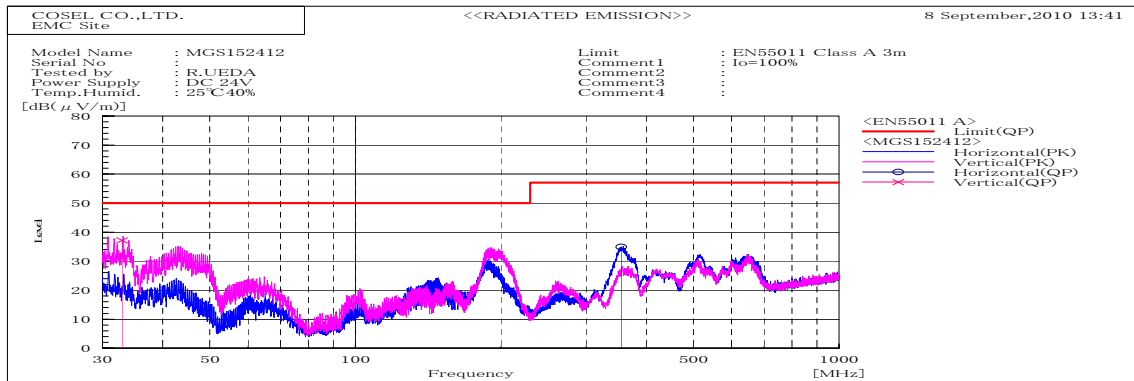


DATA SHEET		Date	21-Sep-10
Model	MGS152412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46079		VA	24.4	23.1	10.1	34.5	33.2	79	66	44.5	32.8	Pass	
28.56215		VB	27	27.2	11	38	38.2	73	60	35	21.8	Pass	
28.56415		VA	27.2	27	10.7	37.9	37.7	73	60	35.1	22.3	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV					
32.923	V	Stable	52	-14.9		37.1		50	12.9	108	0	
354.53	H	Stable	51	-16.1		34.9		57	22.1	101	174	

## DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

### 1. Line conduction



### 2. Radiated emission



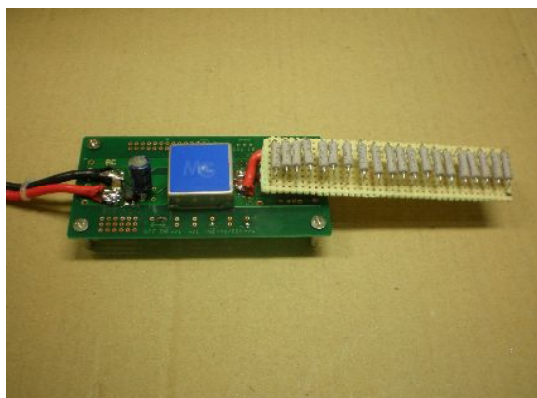


## Conditions

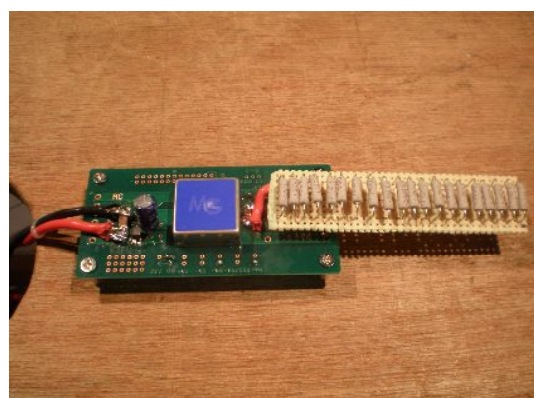
Test : EMI  
Model Name : MGS1524□□/MGW1524□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

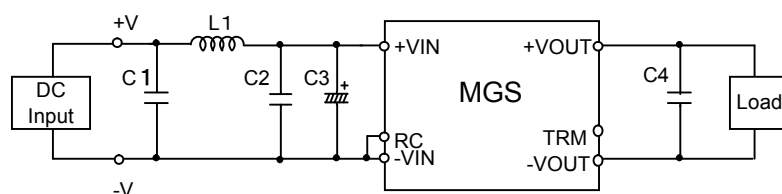


Fig.1 Testing circuitry 1

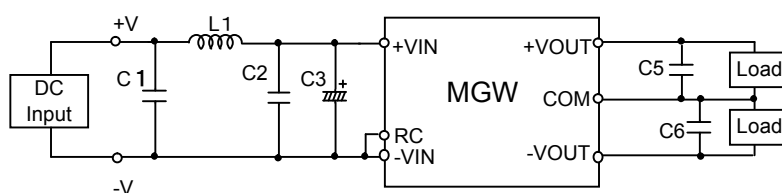


Fig.2 Testing circuitry 2

L1	:	2.2 $\mu$ H	CI4C-2R2	(KORIN ELECTRONICS)
C1,C2	:	50V 6.8 $\mu$ F	C4532X7R1H685MT	(TDK)
C3	:	50V 100 $\mu$ F	LXZ50VB100M	(NIPPON CHEMI-CON)
C4,C5,C6	:	25V 22 $\mu$ F	CM32X5R226K25A	(KYOCERA)